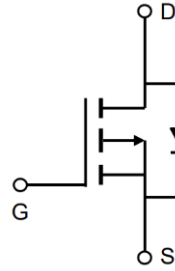


## -30V P-Channel Enhancement Mode MOSFET

### Description

The AP70P03NF uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



### General Features

$V_{DS} = -30V$   $I_D = -70 A$

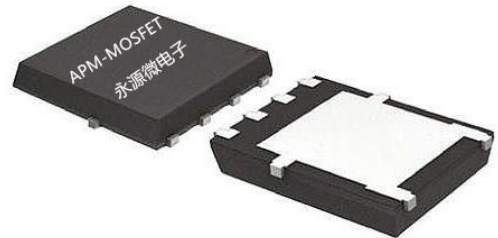
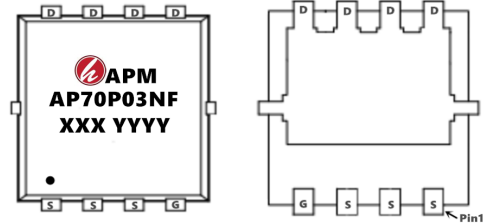
$R_{DS(ON)} < -7.5 m\Omega @ V_{GS} = -10V$

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

| Product ID | Pack       | Marking            | Qty(PCS) |
|------------|------------|--------------------|----------|
| AP70N03NF  | PDFN5*6-8L | AP70P03NF xxx yyyy | 5000     |

### Absolute Maximum Ratings (TC=25°C unless otherwise specified)

| Symbol                    | Parameter   | Rating     | Units        |
|---------------------------|---|------------|--------------|
| $V_{DS}$                  | Drain-Source Voltage  | -30        | V            |
| $V_{GS}$                  | Gate-Source Voltage   | $\pm 20$   | V            |
| $I_D @ T_C = 25^\circ C$  | Continuous Drain Current, $V_{GS} @ -10V^{1,6}$                   | -70        | A            |
| $I_D @ T_C = 100^\circ C$ | Continuous Drain Current, $V_{GS} @ -10V^{1,6}$                   | -50        | A            |
| $I_{DM}$                  | Pulsed Drain Current <sup>2</sup>                                 | -200       | A            |
| EAS                       | Single Pulse Avalanche Energy <sup>3</sup>                        | 80         | mJ           |
| $I_{AS}$                  | Avalanche Current   | -40        | A            |
| $P_D @ T_C = 25^\circ C$  | Total Power Dissipation <sup>4</sup>                              | 90         | W            |
| $T_{STG}$                 | Storage Temperature Range   | -55 to 175 | $^\circ C$   |
| $T_J$                     | Operating Junction Temperature Range                              | -55 to 175 | $^\circ C$   |
| $R_{\theta JA}$           | Thermal Resistance Junction-ambient <sup>1</sup> ( $t \leq 10S$ ) | 20         | $^\circ C/W$ |
|                           | Thermal Resistance Junction-ambient <sup>1</sup> (Steady State)   | 50         | $^\circ C/W$ |

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|                  |   |     |      |
|------------------|---|-----|------|
| R <sub>θJC</sub> | Thermal Resistance Junction-case <sup>1</sup> | 1.6 | °C/W |
|------------------|---|-----|------|

| Symbol              | Parameter                                      | Conditions  | Min. | Typ. | Max. | Unit |
|---------------------|--|---|------|------|------|------|
| BV <sub>DSS</sub>   | Drain-Source Breakdown Voltage                 | V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA   | -30  | ---  | ---  | V    |
| R <sub>DS(ON)</sub> | Static Drain-Source On-Resistance <sup>2</sup> | V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A   | ---  | 5.6  | 7.2  | mΩ   |
|                     |  | V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-15A  | ---  | 9.5  | 12   | mΩ   |
| V <sub>GS(th)</sub> | Gate Threshold Voltage                         | V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA                               | -1.2 | ---  | -2.5 | V    |
| I <sub>DSS</sub>    | Drain-Source Leakage Current                   | V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C                        | ---  | ---  | -1   | uA   |
|                     |  | V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C                        | ---  | ---  | -5   |      |
| I <sub>GSS</sub>    | Gate-Source Leakage Current                    | V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V  | ---  | ---  | ±100 | nA   |
| R <sub>g</sub>      | Gate Resistance                                | V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz  | ---  | 1.2  | ---  | Ω    |
| Q <sub>g</sub>      | Total Gate Charge (-10V)                       | V <sub>DS</sub> =-15V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-18A                      | ---  | 60   | ---  | nC   |
| Q <sub>gs</sub>     | Gate-Source Charge                             |   | ---  | 9    | ---  |      |
| Q <sub>gd</sub>     | Gate-Drain Charge                              |   | ---  | 15   | ---  |      |
| T <sub>d(on)</sub>  | Turn-On Delay Time                             | V <sub>DD</sub> =-15V, V <sub>GS</sub> =-10V, R <sub>g</sub> =3.3, I <sub>D</sub> =-20A | ---  | 17   | ---  | ns   |
| T <sub>r</sub>      | Rise Time                                      |   | ---  | 40   | ---  |      |
| T <sub>d(off)</sub> | Turn-Off Delay Time                            |   | ---  | 55   | ---  |      |
| T <sub>f</sub>      | Fall Time                                      |   | ---  | 13   | ---  |      |
| C <sub>iss</sub>    | Input Capacitance                              | V <sub>DS</sub> =-25V, V <sub>GS</sub> =0V, f=1MHz                                      | ---  | 3450 | ---  | pF   |
| C <sub>oss</sub>    | Output Capacitance                             |   | ---  | 255  | ---  |      |
| C <sub>rss</sub>    | Reverse Transfer Capacitance                   |   | ---  | 140  | ---  |      |
| I <sub>S</sub>      | Continuous Source Current <sup>1,5</sup>       | V <sub>G</sub> =V <sub>D</sub> =0V, Force Current                                       | ---  | ---  | -70  | A    |
| V <sub>SD</sub>     | Diode Forward Voltage <sup>2</sup>             | V <sub>GS</sub> =0V, I <sub>S</sub> =-1A, T <sub>J</sub> =25°C                          | ---  | ---  | -1.2 | V    |
| t <sub>rr</sub>     | Reverse Recovery Time                          | I <sub>F</sub> =-20A, di/dt=100A/μs, T <sub>J</sub> =25°C                               | ---  | 22   | ---  | nS   |
| Q <sub>rr</sub>     | Reverse Recovery Charge                        |   | ---  | 72   | ---  | nC   |

Note :

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3.The EAS data shows Max. rating . The test condition is V<sub>DD</sub>=-50V, V<sub>GS</sub>=-10V, L=0.1mH, I<sub>AS</sub>=-40A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications , should be limited by total power dissipation
- 6.The maximum current rating is package limited.

## -30V P-Channel Enhancement Mode MOSFET

### Typical Characteristics

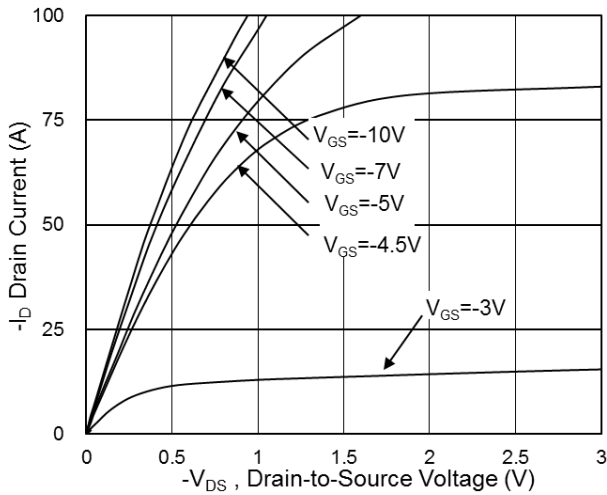


Fig.1 Typical Output Characteristics

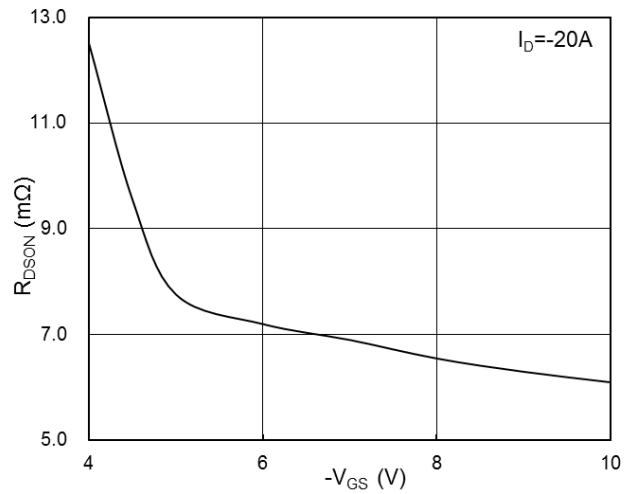


Fig.2 On-Resistance vs. Gate-Source Voltage

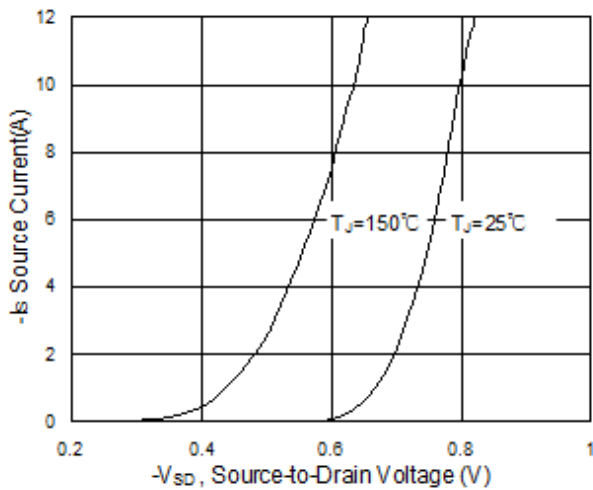


Fig.3 Forward Characteristics of Reverse

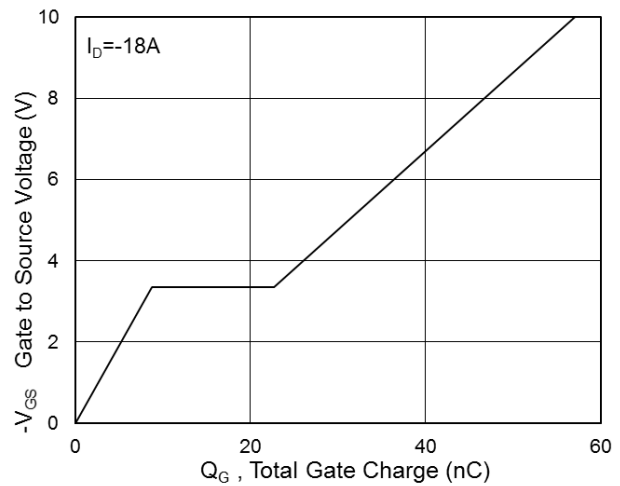


Fig.4 Gate-Charge Characteristics

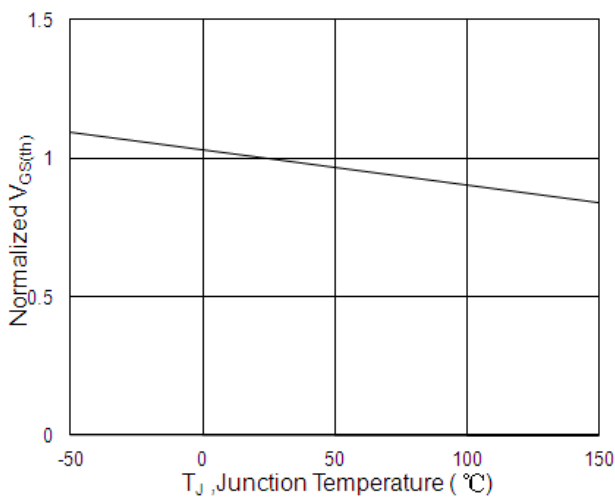


Fig.5 Normalized  $-V_{GS(th)}$  vs.  $T_J$

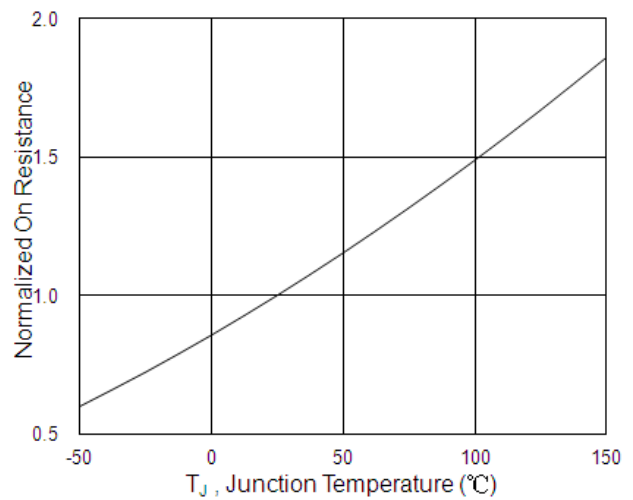
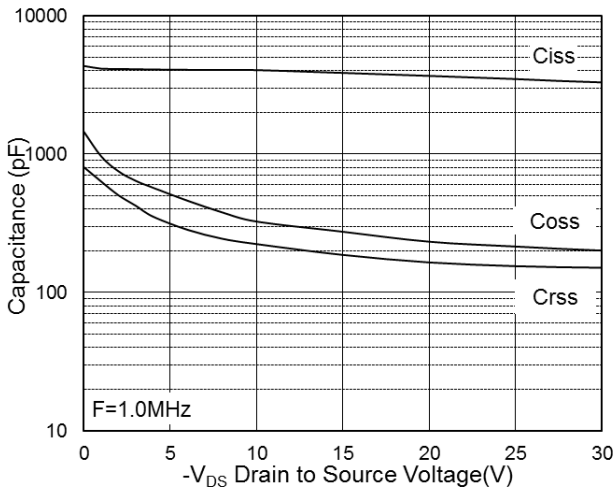


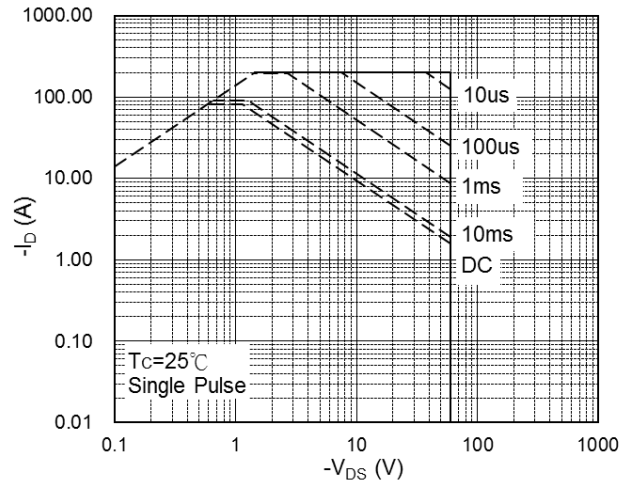
Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$



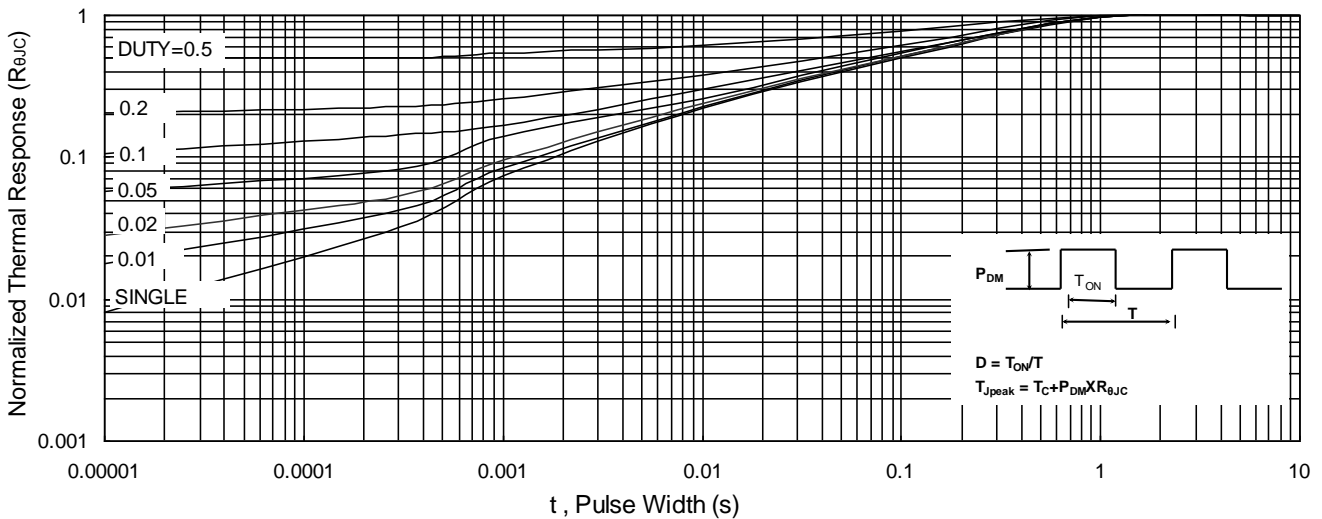
## -30V P-Channel Enhancement Mode MOSFET



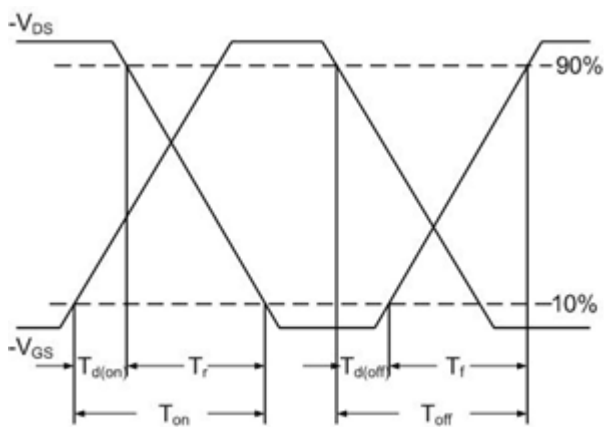
**Fig.7 Capacitance**



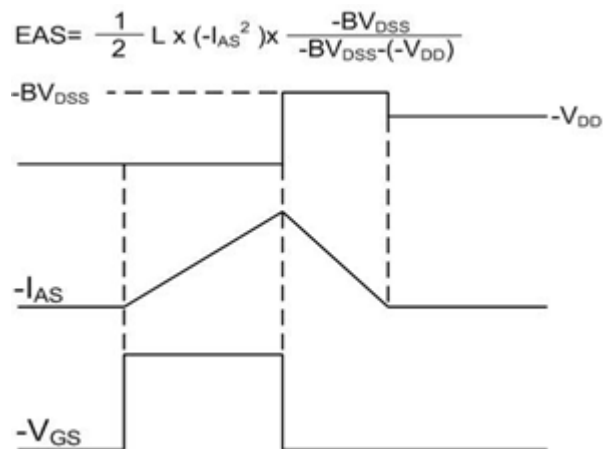
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

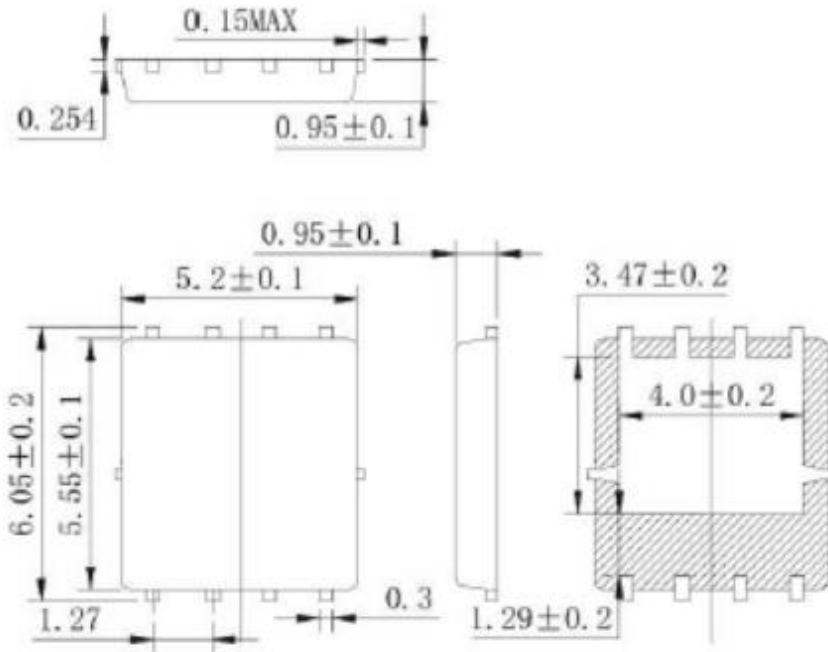


**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**

### DFN5\*6-XW-01



**-30V P-Channel Enhancement Mode MOSFET****Attention**

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